Product data sheet

1. General description

WeEnPACK-B1 module with WeEn 1200V Gen2 SiC MOSFET and Pressfit type. Integrated with NTC temperature sensor.



2. Features and benefits

- · H Bridge topology
- · Press-fit pin type
- Low R_{DSon}
- Low Switching Losses
- Low Q_g and C_{rss}
- Low Inductive Design

3. Applications

- · Power inverters
- AC-DC converters
- · Active power factor correctors
- Motor drives

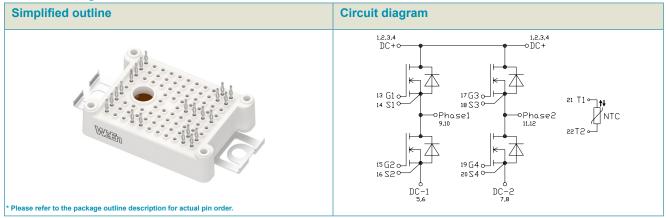
4. Quick reference data

Table 1. Quick reference data

Symbol	Parameter	Conditions	Notes	s Values			Unit
Absolute	maximum rating						
V _{DS}	drain-source voltage	T _j = 25 °C			1200		V
I _D	drain current	V _{GS} = 18 V; T _h = 25 °C			38		Α
P _{tot}	total power dissipation	T _h = 25 °C			74		W
Symbol	Parameter	Conditions	Notes	Min	Тур	Max	Unit
Static ch	aracteristics						
$R_{\text{DS(on)}}$	drain-source on-state resistance	$V_{GS} = 15 \text{ V}; I_D = 33 \text{ A}; T_j = 25 \text{ °C}$		-	40	-	mΩ
Dynamic	characteristics		,				
Q _{G(tot)}	total gate charge	$I_D = 33 \text{ A}; V_{DS} = 800 \text{ V}; V_{GS} = -4 \text{ V}/18 \text{ V};$		-	115	-	nC
Q_{GD}	gate-drain charge	T _j = 25 °C		-	18	-	nC
Source-d	rain diode		,		'		
Q _r	recovered charge	I_{SD} = 33 A; V_{GS} = -4 V/18 V; V_{R} = 600 V; di/dt = 3400 A/μs; $R_{G(ext)}$ = 5.1 Ω; T_{J} = 25 °C		-	465	-	nC

5. Pinning information

Table 2. Pinning information



6. Ordering information

Table 3. Ordering information

Type number	Package Name	Orderable part number	Packing method	Small packing quantity	•	Package issue date
WMSC040F12B1P	WeEnPACK-B1	WMSC040F12B1P6T	Tray	16	WeEnPACK- B1PFB-A	28-Jun-2024

7. Marking

Table 4. Marking codes

Type number	Marking codes
WMSC040F12B1P	WMSC040F12B1P

8. Limiting values

Table 5. Limiting values

In accordance with the Absolute Maximum Rating System (IEC 60134).

Symbol	Parameter	Conditions	Notes	Values	Unit
T_{stg}	storage temperature			-40 to 125	°C
$T_{j.op}$	operating junction temperature			-40 to 150	°C
$T_{j.max}$	maximum junction temperature	Intermittent condition with shortened lifetime		-40 to 175	°C
V _{ISOL}	RMS isolation voltage	T _j = 25 °C; all terminals shorted; f = 50 Hz; t = 1 s		3500	V
MOSFET					•
V_{DS}	drain-source voltage	T _j = 25 °C		1200	V
$V_{\rm GS,max}$	gate-source voltage	Absolute maximum values		-12 to 24	V
$V_{GS,op}$	gate-source voltage	Recommended operational values		-4 to 18	V
P _{tot}	total power dissipation	T _h = 25 °C		74	W
I _D	drain current	V _{GS} = 18 V; T _h = 25 °C		38	Α
		V _{GS} = 18 V; T _h = 100 °C		24	Α
I_{DM}	peak drain current	pulse width tp limited by T _{jmax}		80	А
E _{as}	single pulse drain-to- source avalanche	I_{AS} = 24 A; L = 1 mH; V_{DD} = 100 V; $T_{j(\text{init})}$ = 25 °C; per MOSFET		288	mJ
Body Dioc	le				
I _{SD}	DC body diode forward current	T _h = 25 °C; V _{GS} = -4 V		18	Α
I _{SD,pulse}	Pulse body diode current	verified by design, tp limited by T_{jmax}		80	Α

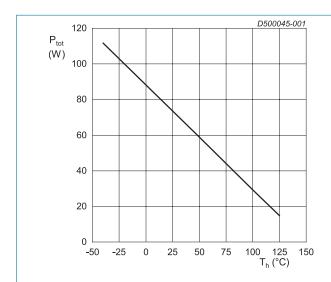


Fig. 1. Power dissipation as a function of heatsink temperature; maximum values

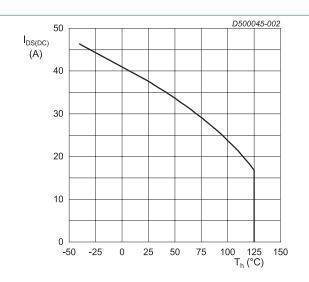


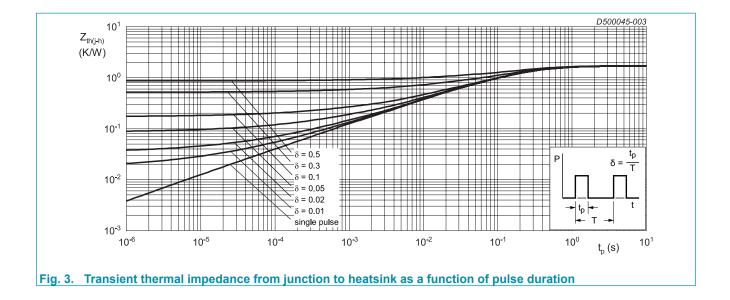
Fig. 2. Continuous Drain Current as a function of heatsink temperature

9. Thermal & Mechanical characteristics

Table 6. Thermal & Mechanical characteristics

Symbol	Parameter	Conditions	Notes	Min	Тур	Max	Unit
R _{th(j-c)}	thermal resistance from junction to case	per MOSFET		-	0.75	-	K/W
R _{th(j-h)}	thermal resistance from junction to heatsink	per MOSFET, $\lambda_{grease} = 3 \text{ W/(m·K)}$ thick _{grease} = 50 um		-	1.7	-	K/W
Internal Is	solation	basic insulation (class 1, IEC 61140)			Al_2O_3		
d _{Creep}	Creepage distance	terminal to heatsink		-	11.5	-	mm
		terminal to terminal		-	6.3	-	mm
d _{Clear}	Clearance	terminal to heatsink		-	10	-	mm
		terminal to terminal		-	5	-	mm
СТІ	Comperative tracking index				>200		
F	Mounting force per clamp			20	-	50	N
G	Approximate Weight			-	20	-	g

Note: Module is ESD sensitive. Handling precautions are recommanded.

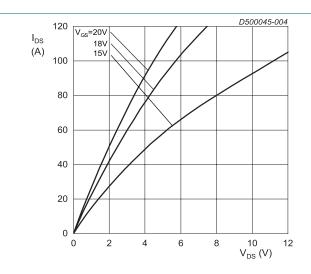


10. Characteristics

Table 7. Characteristics

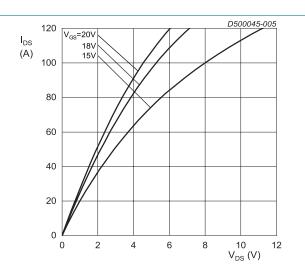
MOSFET	1		1				
Symbol	Parameter	Conditions	Notes	Min	Тур	Max	Unit
Static ch	aracteristics						
$V_{(BR)DSS}$	drain-source breakdown voltage	$I_D = 100 \mu A; V_{GS} = 0 V; T_j = 25 °C$		1200	-	-	V
$V_{\text{GS(th)}}$	gate-source threshold	$I_D = 10 \text{ mA}; V_{DS} = V_{GS}; T_j = 25 \text{ °C}$		1.9	2.6	3.5	V
	voltage	$I_D = 10 \text{ mA}; V_{DS} = V_{GS}; T_j = 175 \text{ °C}$		-	1.9	-	V
I _{DSS}	drain leakage current	V _{DS} = 1200 V; V _{GS} = 0 V; T _j = 25 °C		-	0.2	100	μA
I _{GSS}	gate leakage current	V _{GS} = 24 V; V _{DS} = 0 V; T _j = 25 °C		-	10	100	nA
	(absolute value)	V _{GS} = -12 V; V _{DS} = 0 V; T _j = 25 °C		-	10	100	nA
R _{DS(on)}	drain-source on-state	V _{GS} = 15 V; I _D = 33 A; T _j = 25 °C		-	40	-	mΩ
	resistance	V _{GS} = 18 V; I _D = 33 A; T _j = 25 °C		-	33	45	mΩ
		V _{GS} = 18 V; I _D = 33 A; T _j = 125 °C		-	46	-	mΩ
		V _{GS} = 18 V; I _D = 33 A; T _j = 150 °C		-	51	-	mΩ
		V _{GS} = 18 V; I _D = 33 A; T _j = 175 °C		-	54	-	mΩ
R_G	gate resistance	f = 1 MHz; T _j = 25 °C; per MOSFET		-	1	-	Ω
g _{fs}	transconductance	V _{DS} = 20 V; I _D = 33 A; T _j = 25 °C		-	20	-	S
Dynamic	characteristics		1				
Q _{G(tot)}	total gate charge	I _D = 33 A; V _{DS} = 800 V; V _{GS} = -4 V/18 V;		-	115	-	nC
Q _{GS}	gate-source charge	T _j = 25 °C		-	47	-	nC
Q_{GD}	gate-drain charge			-	18	-	nC
C _{iss}	input capacitance	V _{DS} = 1000 V; V _{GS} = 0 V; f = 100 KHz;		-	2.45	-	nF
C _{oss}	output capacitance	T _j = 25 °C		-	108	-	pF
C _{rss}	reverse transfer capacitance			-	11	-	pF
E _{oss}	Coss stored energy			-	54	-	μJ
t _{d(on)}	turn-on delay time	V _{DS} = 800 V; V _{GS} = -4 V/18 V;		-	27	-	ns
t _r	rise time	$R_{G(ext)} = 5.1 \Omega; I_D = 33 A; L = 300 \mu H;$ $T_i = 25 °C$		-	30	-	ns
$t_{\text{d(off)}}$	turn-off delay time			-	42	-	ns
t _f	fall time			-	11	-	ns
E _{on}	turn-on energy			-	612	-	μJ
E _{off}	turn-off energy			-	90	-	μJ

Body dic	ode						
Symbol	Parameter	Conditions	Notes	Min	Тур	Max	Unit
Static ch	aracteristics		,		•		
V_{SD}	source-drain voltage	$V_{GS} = -4 \text{ V; } I_{SD} = 33 \text{ A; } T_j = 25 \text{ °C}$		-	5.5	-	V
		V_{GS} = -4 V; I_{SD} = 33 A; T_j = 150 °C		-	5.0	-	V
Dynamic	characteristics		'		'	'	
I _{rrm}	reverse recovery current	I_{SD} = 33 A; V_{GS} = -4 V/18 V; V_{R} = 600 V;		-	44	-	Α
t _{rr}	reverse recovery time	di/dt = 3400 A/μs; $R_{G(ext)}$ = 5.1 Ω; T_i = 25 °C		-	19	-	ns
Q _r	recovered charge	1		-	465	-	nC
E _{rec}	reverse recovery energy			-	117	-	μJ
NTC ther	mistor		'				
Symbol	Parameter	Conditions	Notes	Min	Тур	Max	Unit
R ₂₅	Rated resistance	T _{NTC} = 25 °C		-	5000	-	Ω
R ₁₀₀		T _{NTC} = 100 °C			465±5%)	Ω
B _{25/50}	B-value	$R_2 = R_{25} \exp[B_{25/50}(1/T_2 - 1/(298.15K))]$		3380		K	
	Maximum operating temperature			-	200	-	°C
	Dissipation costant			-	2	-	mW/K
	Thermal time constant			-	≤10	-	s



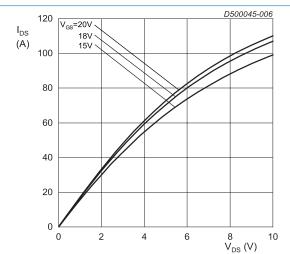
 $T_j = -40 \, ^{\circ}\text{C}; t_p < 200 \, \mu\text{s}$

Fig. 4. Output characteristics; drain current as a function of drain-source voltage; typical values

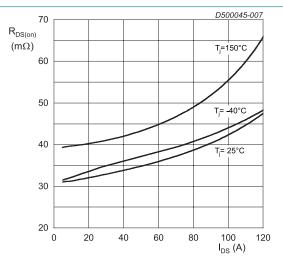


 $T_j = 25 \, ^{\circ}C; t_p < 200 \, \mu s$

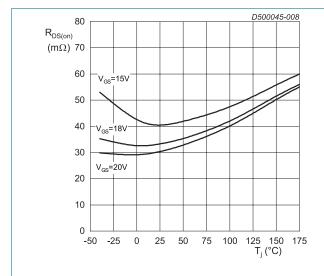
Fig. 5. Output characteristics; drain current as a function of drain-source voltage; typical values



 $T_i = 150 \, ^{\circ}\text{C}; t_p < 200 \, \mu\text{s}$ Fig. 6. Output characteristics; drain current as a function of drain-source voltage; typical values

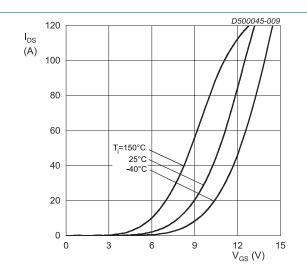


 $V_{GS} = 18 \ V; \ t_p < 200 \ \mu s$ Fig. 7. Drain-source on-state resistance as a function of drain current; typical values



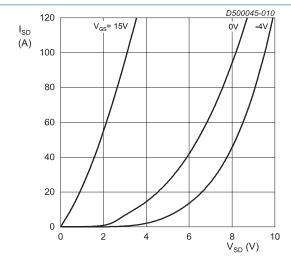
 I_{DS} = 33 A; t_p < 200 μ s

Fig. 8. Drain-source on-state resistance as a function of junction temperature



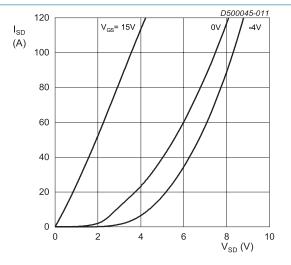
 $V_{DS} = 20 \text{ V}; t_p < 200 \text{ }\mu\text{s}$

Fig. 9. Transfer characteristics; drain current as a function of gate-source voltage; typical values



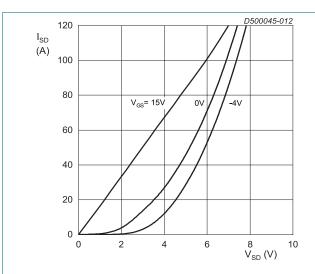
 $T_j = -40 \, ^{\circ}\text{C}; \, t_p < 200 \, \mu\text{s}$

Fig. 10. Body diode forward characteristics; typical values

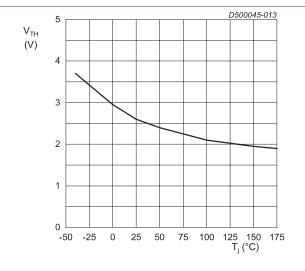


 $T_j = 25 \, ^{\circ}\text{C}; t_p < 200 \, \mu\text{s}$

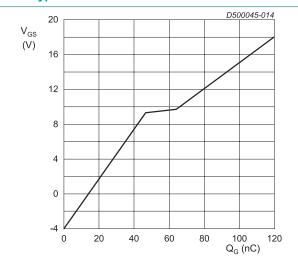
Fig. 11. Body diode forward characteristics; typical values



T_j = 150 °C; t_p < 200 μs Fig. 12. Body diode forward characteristics; typical values



V_{DS} = 10 V; I_{DS} = 10 mA Fig. 13. Threshold voltage as a function of junction temperature



 I_{DS} = 33 A; I_{GS} = 0.1 mA; V_{DS} = 800 V; T_j = 25 °C Fig. 14. Gate-source voltage as a function of gate charge; typical values

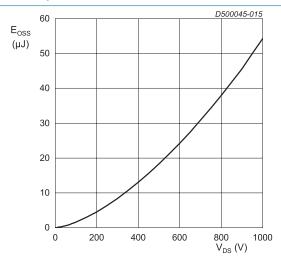
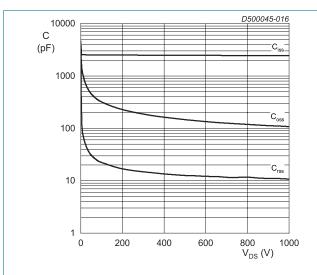
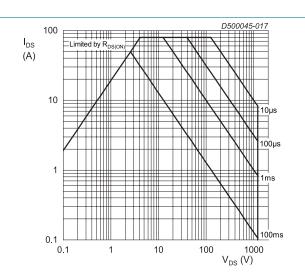


Fig. 15. Output capacitor stored energy as a function of drain-source voltage



 $V_{DS} = 0 - 1000 \text{ V}$

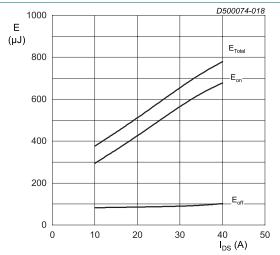
 $T_j = 25 \text{ °C}; V_{AC} = 25 \text{ mV}; f = 100 \text{ KHz}$



 $T_j = 25 \,^{\circ}\text{C}; D = 0$ Parameter: t_D

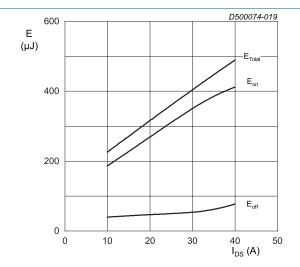
Fig. 17. Forward bias safe operating area





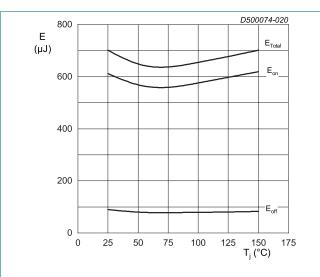
 T_j = 25 °C; V_{DD} = 800 V; $R_{G(ext)}$ = 5.1 $\Omega;$ $R_{G(on)}$ = 5.1 $\Omega;$ V_{GS} = -4 V/18 V; L = 300 μH

Fig. 18. Clamped Inductive Switching Energy as a function of drain current



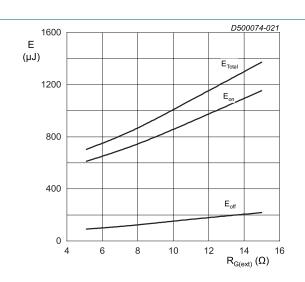
 T_{j} = 25 °C; V_{DD} = 600 V; $R_{G(off)}$ = 5.1 $\Omega;$ $R_{G(on)}$ = 5.1 $\Omega;$ V_{GS} = -4 V/18 V; L = 300 μH

Fig. 19. Clamped Inductive Switching Energy as a function of drain current



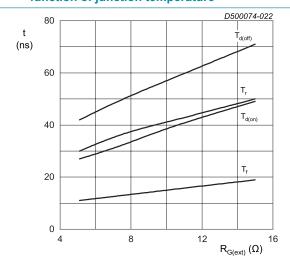
 $I_{DS}=33$ A; $V_{DD}=800$ V; $R_{G(off)}=5.1$ $\Omega;$ $R_{G(on)}=5.1$ $\Omega;$ $V_{GS}=$ -4 V/18 V; $L=300~\mu H$

Fig. 20. Clamped Inductive Switching Energy as a function of junction temperature



 T_{j} = 25 °C; V_{DD} = 800 V; I_{DS} = 33 A; V_{GS} = -4 V/18 V; L = 300 μH

Fig. 21. Clamped Inductive Switching Energy as a function of external gate resistance



 T_{j} = 25 °C; V_{DD} = 800 V; I_{DS} = 33 A; V_{GS} = -4 V/18 V; L = 300 μH

Fig. 22. Switching time as a function of external gate resistance

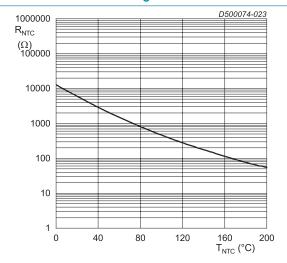
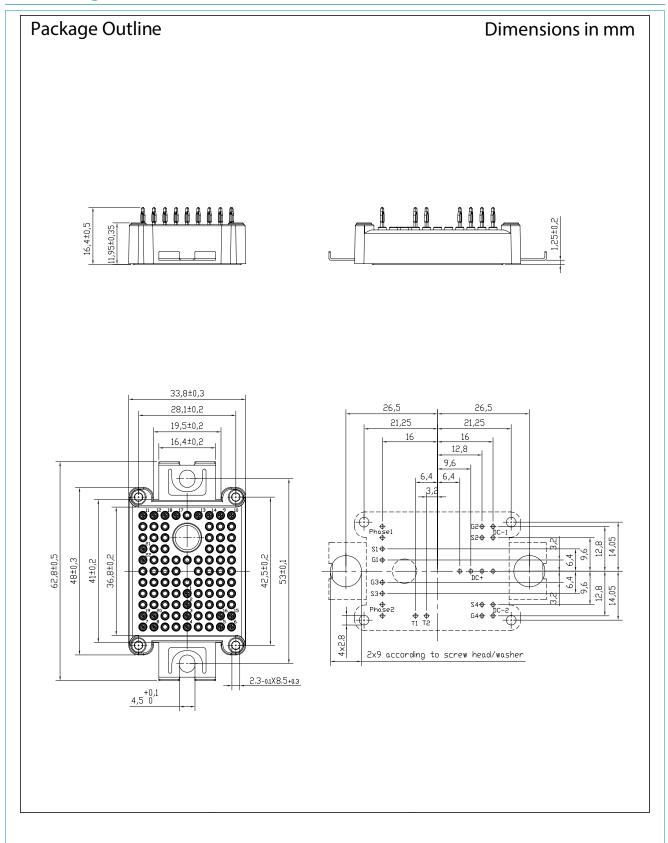


Fig. 23. NTC thermistor resistance as a function of NTC temperature

11. Package outline



12. Legal information

Data sheet status

Document status [1][2]	Product status [3]	Definition
Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
Preliminary [short] data sheet	Qualification	This document contains data from the preliminary specification.
Product [short] data sheet	Production	This document contains the product specification.

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- [2] The term 'short data sheet' is explained in section "Definitions".
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WMSC040F12B1P

N-Channel Silicon Carbide MOSFET Module

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For more information, please visit: http://www.ween-semi.com For sales office addresses, please send an email to: salesaddresses@ween-semi.com Date of release: 24 September 2024

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